

Additional Information



Resources







Accessories

Samples

Functional Diagram



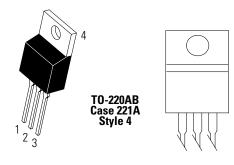
Description

Designed primarily for half-wave ac control applications, such as motor controls, heating controls, and power supplies; or wherever half-wave, silicon gate-controlled devices are needed.

Features

- Blocking Voltage to 800 Volts
- On-State Current Rating of 16 Amperes RMS
- High Surge Current Capability160 Amperes
- Rugged Economical TO-220AB Package
- Glass Passivated Junctions for Reliability and Uniformity
- Minimum and Maximum Values of IGT, VGT, and IH Specified for Ease of Design
- High Immunity to dv/dt 100 V/µsec Minimum at 125°C
- These are Pb-Free Devices

Pin Out





Maximum Ratings (T₁ = 25°C unless otherwise noted)

_	J			
Rating		Symbol	Value	Unit
Peak Repetitive Off-State Voltage (Note 1) (- 40 to 125°C, Sine Wave, 50 to 60 Hz, Gate Open)	MCR16NG	V _{DRM} , V _{RRM}	800	V
On-State RMS Current (180° Conduction Angles; $T_c = 80$ °C)		I _{T (RMS)}	16	А
Peak Non-Repetitive Surge Current (1/2 Cycle, Sine Wave 60 Hz, $T_J = 125$ °C)		I _{TSM}	160	А
Circuit Fusing Consideration (t = 8.3 ms)		l²t	106	A ² sec
Forward Peak Gate Power (Pulse Width $\leq 1.0 \mu sec$, $T_c = 80^{\circ} C$		P _{GM}	5.0	W
Forward Average Gate Power (t = 8.3 msec, $T_c = 80$ °C)		P _{G (AV)}	0.5	W
Forward Peak Gate Current (Pulse Width \leq 1.0 μ sec, T_c = 80°C)	I _{GM}	2.0	А
Operating Junction Temperature Range		T _J	-40 to 125	°C
Storage Temperature Range		T _{stq}	-40 to 150	°C

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

Thermal Characteristics

Rating		Symbol	Value	Unit
Thermal Resistance	Junction-to-Case (AC) Junction-to-Ambient	R _{BJC} R _{BJA}	1.5 62.5	°C/W
Maximum Lead Temperature for Soldering Purposes, 1/8" from case for 10 seconds		T_L	260	°C

Electrical Characteristics - OFF (T_C = 25°C unless otherwise noted)

Characteristic		Symbol	Min	Тур	Max	Unit
Peak Repetitive Forward or Reverse Blocking Current	T ₁ = 25°C	l _{DRM} ,	-	-	0.01	mA
$(V_{AK} = V_{DRM} = V_{RRM}; Gate Open)$	T」= 125°C	I	-	-	2.0	mA

Electrical Characteristics - ON $(T_J = 25^{\circ}C)$ unless otherwise noted; Electricals apply in both directions)

Characteristic	Symbol	Min	Тур	Max	Unit
Peak Forward On–State Voltage (Note 2) ($I_{TM} = 32 \text{ A}$)	V_{TM}	_	_	1.7	V
Gate Trigger Current (Continuous dc) ($V_D = 12 \text{ V; R}_L = 100 \Omega$)	I _{GT}	2.0	10	20	mA
Holding Current (Anode Voltage = 12 V, Initiating Current = 200 mA, Gate Open)	I _H	4.0	25	40	mA
Latch Current ($V_D = 12 \text{ V}$, $I_G = 200 \text{ mA}$)	IL	_	30	60	mA
Gate Trigger Voltage (Continuous dc) ($V_D = 12 \text{ V}, R_L = 100 \Omega$)	$V_{\rm GT}$	0.5	0.65	1.0	V

Dynamic Characteristics

Characteristic	Symbol	Min	Тур	Max	Unit
Critical Rate of Rise of Off–State Voltage (V _D = Rated V _{DRM} , Exponential Waveform, Gate Open, T _J = 125°C)	dv/dt	100	300	_	V/µs
Critical Rate of Rise of On–State Current ($I_{PK} = 50 \text{ A}$, $PW = 30 \mu sec$, $diG/dt = 1 \text{ A/}\mu sec$, $dig/dt = 1 $	di/dt	_	_	50	A/µs

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

2. Pulse Test; Pulse Width ≤ 2.0 msec, Duty Cycle ≤ 2%.

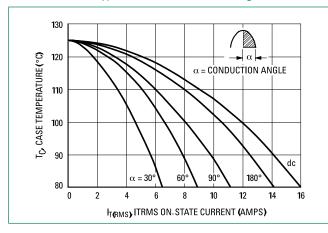


^{1.} V_{cold} and V_{cold} for all types can be applied on a continuous basis. Ratings apply for zero or negative gate voltage; however, positive gate voltage shall not be applied concurrent with negative potential on the anode. Blocking voltages shall not be tested with a constant current source such that the voltage ratings of the devices are exceeded.

Voltage Current Characteristic of SCR

Symbol	Parameter
V_{DRM}	Peak Repetitive Forward Off State Voltage
I _{DRM}	Peak Forward Blocking Current
V_{RRM}	Peak Repetitive Reverse Off State Voltage
I _{RRM}	Peak Reverse Blocking Current
V_{TM}	Maximum On State Voltage
I _H	Holding Current

Figure 1.Typical RMS Current Derating



Reverse Blocking Region (off state)

Reverse Avalanche Region
Anode –

+ Current

Figure 2.On–State Power Dissipation

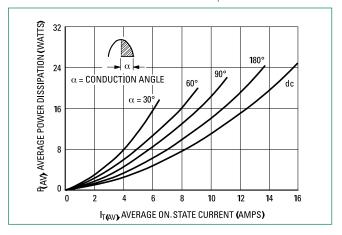


Figure 3.Transient Thermal Response

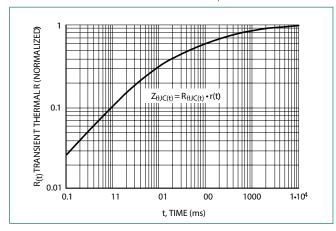


Figure 4.Typical Holding Current vs Junction Temperature

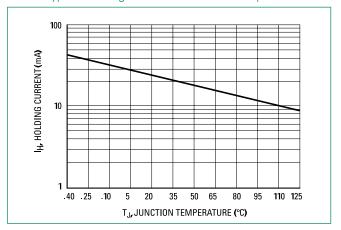


Figure 5. Typical On–State Characteristics

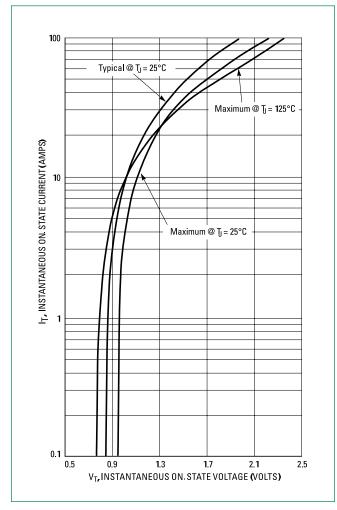


Figure 6.Typical Latching Current vs Junction Temperature

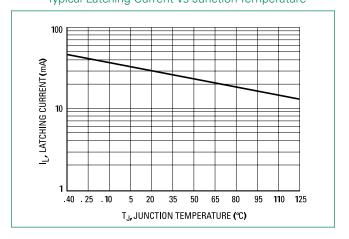


Figure 7.Typical Gate Trigger Current vs Junction Temperature

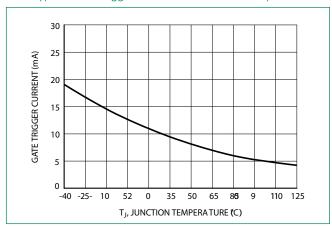


Figure 8.Typical Gate Trigger Voltage vs Junction Temperature

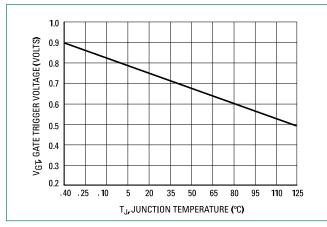


Figure 9.Maximum Non-Repetitive Surge Current

